Substitute forms PTO/SB/08a & PTO/SB/08b	Application Number	10/701,950
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INFORMATION DISCLOSURE	First Named Inventor	Elmer G. Fridrich
STATEMENT BY APPLICANT	Art Unit	2879
	Examiner Name	
Sheet 1 OF 1	Practitioner Docket No.	EF-101 <i>E</i>

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